

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
S1	7	"6162735"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/11/29 14:59
S2	2	("6288393").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/08/01 16:23
S3	3364	382/141-151.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/11/29 11:59
S4	8041	438/6-17.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/11/29 13:23
S5	45	438/6-17.ccls. and sem and fib and substrate	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/11/29 13:24
S6	54	438/6-17.ccls. and sem and fib	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/11/29 13:35
S7	1569	438/6-17.ccls. and substrate same remov\$3	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/11/29 13:36
S8	106	438/6-17.ccls. and substrate same remov\$3 and fail\$3 same detect\$3	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/11/29 13:36
S9	16	gilfeather-glen.in.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/11/29 14:19
S10	43	"5430305"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/11/29 14:24

S11	2	("4875209").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/11/29 14:24
S12	2	("5557559").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/11/29 14:25
S13	2	("6255124").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/11/29 14:25
S14	2	("6078183").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/11/29 14:26
S15	1081	state and chang\$3 and circuit\$3 and defect and fail\$3 and substrate.cm.	US-PGPUB	OR	OFF	2005/11/29 15:01
S16	136	state and chang\$3 and circuit\$3 and defect and fail\$3 and substrate and image\$2 and three and dimension\$3.cm.	US-PGPUB	OR	OFF	2005/11/29 15:01
S17	27	state and chang\$3 and circuit\$3 and defect and fail\$3 and substrate and image\$2 and three and dimension\$3 and die.cm.	US-PGPUB	OR	OFF	2005/11/29 15:01

Day : Tuesday
Date: 11/29/2005


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Time: 13:38:41

Inventor Name Search Result

Your Search was:

Last Name = GILFEATHER

First Name = GLEN

Application#	Patent#	Status	Date Filed	Title	Inventor Name
<u>07050979</u>	4819047	150	05/15/1987	PROTECTION SYSTEM FOR CMOS INTEGRATED CIRCUITS	GILFEATHER, GLEN
<u>07212282</u>	4870530	150	06/27/1988	ELECTROSTATIC DISCHARGE PROTECTION CIRCUITRY FOR ANY TWO EXTERNAL PINS OF AN I.C. PACKAGE	GILFEATHER, GLEN
<u>08988868</u>	5972725	250	12/11/1997	DEVICE ANALYSIS FOR FACE DOWN CHIP	GILFEATHER, GLEN
<u>09050531</u>	6069366	150	03/30/1998	ENDPOINT DETECTION FOR THINNING OF SILICON OF A FLIP CHIP BONDED INTEGRATED CIRCUIT	GILFEATHER, GLEN
<u>09074627</u>	6171944	250	05/07/1998	A METHOD FOR BRINGING UP LOWER LEVEL METAL NODES OF MULTI-LAYERED INTEGRATED CIRCUITS FOR SIGNAL ACQUISITION	GILFEATHER, GLEN
<u>09383790</u>	6372627	150	08/26/1999	ARRANGEMENT AND METHOD FOR CHARACTERIZATION OF FOCUSED-ION-BEAM INSULATOR DEPOSITION.	GILFEATHER, GLEN
<u>09409089</u>	6352871	150	09/30/1999	PROBE GRID FOR INTEGRATED CIRCUIT EXCITATION	GILFEATHER, GLEN
<u>09409982</u>	6455334	150	09/30/1999	PROBE GRID FOR INTEGRATED CIRCUIT ANALYSIS	GILFEATHER, GLEN
<u>09578195</u>	6285036	150	05/24/2000	Endpoint detection for thinning of silicon of a flip chip bonded integrated circuit	GILFEATHER, GLEN

09580716	6469529	150	05/30/2000	TIME-RESOLVED EMISSION MICROSCOPY SYSTEM	GILFEATHER, GLEN
09826576	6518661	150	04/05/2001	APPARATUS FOR METAL STACK THERMAL MANAGEMENT IN SEMICONDUCTOR DEVICES	GILFEATHER, GLEN
09833247	Not Issued	71	04/11/2001	Three-dimensional tomography	GILFEATHER, GLEN
09833250	6566888	150	04/11/2001	REPAIR OF RESISTIVE ELECTRICAL CONNECTIONS IN AN INTEGRATED CIRCUIT	GILFEATHER, GLEN
10261390	6897664	150	09/30/2002	LASER BEAM INDUCED PHENOMENA DETECTION	GILFEATHER, GLEN
10324328	6833718	150	12/20/2002	PHOTON BEACON	GILFEATHER, GLEN
60198365	Not Issued	159	04/19/2000	Semiconductor analysis arrangement and analysis therefor	GILFEATHER, GLEN P
09838667	Not Issued	161	04/19/2001	Semiconductor analysis using thermal control	GILFEATHER, GLEN P.
09838671	6700659	150	04/19/2001	SEMICONDUCTOR ANALYSIS ARRANGEMENT AND METHOD THEREFOR	GILFEATHER, GLEN P.
09838672	6635839	150	04/19/2001	SEMICONDUCTOR ANALYSIS ARRANGEMENT AND METHOD THEREFOR	GILFEATHER, GLEN P.
09838717	6844928	150	04/19/2001	FIBER OPTIC SEMICONDUCTOR ANALYSIS ARRANGEMENT AND METHOD THEREFOR	GILFEATHER, GLEN P.
09887638	6716683	150	06/22/2001	OPTICAL ANALYSIS FOR SOI INTEGRATED CIRCUITS	GILFEATHER, GLEN P.
09694523	6661246	150	10/23/2000	CONSTANT-CURRENT VDDQ TESTING OF INTEGRATED CIRCUITS	GILFEATHER, GLEN PATRICK

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Inventor Name Search Result

Your Search was:

Last Name = BRUCE

First Name = VICTORIA

Application#	Patent#	Status	Date Filed	Title	Inventor Name
<u>09247001</u>	6417068	150	02/08/1999	SEMICONDUCTOR DEVICE NAVIGATION USING LASER SCRIBING	BRUCE, VICTORIA
<u>09273954</u>	Not Issued	161	03/22/1999	MARKER IMPLANTATION FOR IMPROVED END- POINTDETECTION	BRUCE, VICTORIA
<u>09838667</u>	Not Issued	161	04/19/2001	Semiconductor analysis using thermal control	BRUCE, VICTORIA
<u>09838671</u>	6700659	150	04/19/2001	SEMICONDUCTOR ANALYSIS ARRANGEMENT AND METHOD THEREFOR	BRUCE, VICTORIA
<u>09838672</u>	6635839	150	04/19/2001	SEMICONDUCTOR ANALYSIS ARRANGEMENT AND METHOD THEREFOR	BRUCE, VICTORIA
<u>09838717</u>	6844928	150	04/19/2001	FIBER OPTIC SEMICONDUCTOR ANALYSIS ARRANGEMENT AND METHOD THEREFOR	BRUCE, VICTORIA
<u>60198365</u>	Not Issued	159	04/19/2000	Semiconductor analysis arrangement and analysis therefor	BRUCE, VICTORIA
<u>09385774</u>	6410349	150	08/30/1999	INTERNAL ANTI- REFLECTIVE COATING FOR INTERFERENCE REDUCTION	BRUCE, VICTORIA J
<u>09052221</u>	6107107	150	03/31/1998	ANALYZING AN ELECTRONIC CIRCUIT FORMED UPON A FRONTSIDE SURFACE OF A SEMICONDUCTOR SUBSTRATE BY DETECTING RADIATION EXITING A BACKSIDE SURFACE COATED WITH AN ANTIREFLECTIVE MATERIAL	BRUCE, VICTORIA J

<u>09578195</u>	<u>6285036</u>	150	05/24/2000	Endpoint detection for thinning of silicon of a flip chip bonded integrated circuit	BRUCE, VICTORIA J.
<u>09586505</u>	<u>6549022</u>	150	06/02/2000	APPARATUS AND METHOD FOR ANALYZING FUNCTIONAL FAILURES IN INTEGRATED CIRCUITS	BRUCE, VICTORIA J.
<u>09586518</u>	Not Issued	95	06/02/2000	RESISTIVITY ANALYSIS	BRUCE, VICTORIA J.
<u>09586572</u>	<u>6546513</u>	150	06/02/2000	DATA PROCESSING DEVICE TEST APPARATUS AND METHOD THEREFOR	BRUCE, VICTORIA J.
<u>09654823</u>	<u>6375347</u>	150	09/05/2000	METHOD FOR LASER SCANNING FLIP-CHIP INTEGRATED CIRCUITS	BRUCE, VICTORIA J.
<u>09766472</u>	Not Issued	163	01/19/2001	Semiconductor die analysis using above band-gap energy	BRUCE, VICTORIA J.
<u>09833247</u>	Not Issued	71	04/11/2001	Three-dimensional tomography	BRUCE, VICTORIA J.
<u>10084100</u>	<u>6617862</u>	150	02/27/2002	LASER INTRUSIVE TECHNIQUE FOR LOCATING SPECIFIC INTEGRATED CIRCUIT CURRENT PATHS	BRUCE, VICTORIA J.
<u>10164739</u>	<u>6870379</u>	150	06/06/2002	INDIRECT STIMULATION OF AN INTEGRATED CIRCUIT DIE	BRUCE, VICTORIA J.
<u>60307995</u>	Not Issued	159	07/26/2001	Indirect stimulation of an integrated circuit die	BRUCE, VICTORIA J.
<u>07826992</u>	<u>5301006</u>	150	01/28/1992	EMISSION MICROSCOPE	BRUCE, VICTORIA J.
<u>07827732</u>	Not Issued	166	01/28/1992	ENERGY RESOLVED EMISSION MICROSCOPY SYSTEM AND METHOD	BRUCE, VICTORIA J.
<u>08104245</u>	Not Issued	166	08/09/1993	ENERGY RESOLVED EMISSION MICROSCOPY SYSTEM AND METHOD	BRUCE, VICTORIA J.
<u>08350381</u>	<u>5661520</u>	250	12/05/1994	ENERGY RESOLVED EMISSION MICROSCOPY SYSTEM AND METHOD	BRUCE, VICTORIA J.
<u>09050531</u>	<u>6069366</u>	150	03/30/1998	ENDPOINT DETECTION FOR THINNING OF SILICON OF A FLIP CHIP BONDED INTEGRATED CIRCUIT	BRUCE, VICTORIA J.
<u>09187314</u>	<u>6146014</u>	250	11/04/1998	METHOD FOR LASER	BRUCE, VICTORIA

				SCANNING FLIP-CHIP INTEGRATED CIRCUITS	J.
<u>09383725</u>	<u>6350982</u>	150	08/26/1999	INDUCEMENT AND DETECTION OF LATCH-UP USING A LASER SCANNING MICROSCOPE	BRUCE, VICTORIA J.
<u>09383733</u>	<u>6348364</u>	150	08/26/1999	NAVIGATION USING 3-D DETECTABLE PATTERN	BRUCE, VICTORIA J.
<u>09383782</u>	<u>6545490</u>	150	08/26/1999	TRENCH-FILLED PROBE POINT FOR A SEMICONDUCTOR DEVICE	BRUCE, VICTORIA J.
<u>09383793</u>	Not Issued	161	08/26/1999	PROBE REGION METHOD AND APPARATUS	BRUCE, VICTORIA J.
<u>09409088</u>	<u>6483327</u>	150	09/30/1999	QUADRANT AVALANCHE PHOTODIODE TIME- RESOLVED DETECTION	BRUCE, VICTORIA J.
<u>10209844</u>	<u>6714294</u>	150	07/31/2002	DE BROGLIE MICROSCOPE	BRUCE, VICTORIA JEAN
<u>09166266</u>	<u>6300148</u>	250	10/05/1998	SEMICONDUCTOR STRUCTURE WITH A BACKSIDE PROTECTIVE LAYER AND BACKSIDE PROBES AND A METHOD FOR CONSTRUCTING THE STRUCTURE	BRUCE, VICTORIA JEAN
<u>09166833</u>	Not Issued	163	10/05/1998	ENDPOINT DETECTION FOR THINNING OF A FLIP CHIP BONDED INTEGRATED CIRCUIT	BRUCE, VICTORIA JEAN
<u>09249367</u>	<u>6210981</u>	150	02/12/1999	METHOD FOR ETCHING A FLIP CHIP USING SECONDARY PARTICLE EMISSIONS TO DETECT THE ETCH END - POINT	BRUCE, VICTORIA JEAN

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Inventor Name Search Result

Your Search was:

Last Name = BRUCE

First Name = MICHAEL

Application#	Patent#	Status	Date Filed	Title	Inventor Name
<u>60162125</u>	Not Issued	159	10/29/1999	SYSTEM AND METHOD FOR DEFINING AUTOMATED ACCESS PROTOCOLS FOR ELECTRONIC TRANSACTIONS WITH MULTIPLE MERCHANTS	BRUCE SR., MICHAEL GEORGE
<u>09259542</u>	<u>6177989</u>	150	03/01/1999	LASER INDUCED CURRENT FOR SEMICONDUCTOR DEFECT DETECTION	BRUCE, MICHAEL
<u>09838667</u>	Not Issued	161	04/19/2001	Semiconductor analysis using thermal control	BRUCE, MICHAEL
<u>09838671</u>	<u>6700659</u>	150	04/19/2001	SEMICONDUCTOR ANALYSIS ARRANGEMENT AND METHOD THEREFOR	BRUCE, MICHAEL
<u>09838672</u>	<u>6635839</u>	150	04/19/2001	SEMICONDUCTOR ANALYSIS ARRANGEMENT AND METHOD THEREFOR	BRUCE, MICHAEL
<u>09838717</u>	<u>6844928</u>	150	04/19/2001	FIBER OPTIC SEMICONDUCTOR ANALYSIS ARRANGEMENT AND METHOD THEREFOR	BRUCE, MICHAEL
<u>10147317</u>	Not Issued	41	05/17/2002	Examining chemical reactions	BRUCE, MICHAEL
<u>10231560</u>	Not Issued	94	08/30/2002	THERMALLY CONDUCTIVE INTEGRATED CIRCUIT MOUNTING STRUCTURES	BRUCE, MICHAEL
<u>10261390</u>	<u>6897664</u>	150	09/30/2002	LASER BEAM INDUCED PHENOMENA DETECTION	BRUCE, MICHAEL
<u>60035667</u>	Not Issued	159	01/21/1997	PREDICTIVE COLLISION SENSING FOR DEPLOYING ACTIVE SAFETY SYSTEMS FOR AUTOMOBILE	BRUCE, MICHAEL
<u>60198365</u>	Not	159	04/19/2000	Semiconductor analysis	BRUCE, MICHAEL

	Issued			arrangement and analysis therefor	
<u>09003672</u>	<u>6056079</u>	150	01/07/1998	AUTOMOTIVE SEAT WEIGHT SENSING SYSTEM	BRUCE, MICHAEL P.
<u>06920178</u>	Not Issued	161	10/17/1986	TAMPER PROOF LIQUID STAIN SEAL	BRUCE, MICHAEL B.
<u>09698072</u>	Not Issued	71	10/30/2000	System and method of aggregate electronic transactions with multiple sources	BRUCE, MICHAEL GEORGE
<u>09698073</u>	Not Issued	160	10/30/2000	System and method of data exchange for electronic transactions with multiple sources	BRUCE, MICHAEL GEORGE
<u>09917810</u>	Not Issued	41	07/31/2001	System and method of data exchange for electronic transactions with multiple sources	BRUCE, MICHAEL GEORGE
<u>60420374</u>	Not Issued	159	10/22/2002	Programmable alarm audio device	BRUCE, MICHAEL L.
<u>08841521</u>	<u>6005958</u>	150	04/23/1997	OCCUPANT TYPE AND POSITION DETECTION SYSTEM	BRUCE, MICHAEL P.
<u>60256777</u>	Not Issued	159	12/18/2000	Self-powered crash sensing module	BRUCE, MICHAEL P.
<u>08878090</u>	<u>6070113</u>	150	06/18/1997	HYBRID VEHICLE CRASH DISCRIMINATION SYSTEM	BRUCE, MICHAEL P.
<u>09009035</u>	<u>6085151</u>	150	01/20/1998	PREDICTIVE COLLISION SENSING SYSTEM	BRUCE, MICHAEL P.
<u>09018256</u>	<u>5979586</u>	150	02/04/1998	VEHICLE COLLISION WARNING SYSTEM	BRUCE, MICHAEL P.
<u>09368251</u>	<u>6198998</u>	250	08/03/1999	OCCUPANT TYPE AND POSITION DETECTION SYSTEM	BRUCE, MICHAEL P.
<u>60020489</u>	Not Issued	159	06/21/1996	HYBRID VEHICLE CRASH DISCRIMINATION SYSTEM	BRUCE, MICHAEL P.
<u>60034018</u>	Not Issued	159	01/08/1997	AUTOMOTIVE SEAT WEIGHT SENSING SYSTEM	BRUCE, MICHAEL P.
<u>60037299</u>	Not Issued	159	02/05/1997	WARNING SYSTEM FOR VEHICLE COLLISION PREDICTION	BRUCE, MICHAEL P.
<u>09520597</u>	<u>6488405</u>	150	03/08/2000	FLIP CHIP DEFECT ANALYSIS USING LIQUID CRYSTAL	BRUCE, MICHAEL R.
<u>09011080</u>	Not Issued	161	01/27/1998	CHOCOLATE WITH RAISED DESIGN	BRUCE, MICHAEL R.

<u>09580716</u>	<u>6469529</u>	150	05/30/2000	TIME-RESOLVED EMISSION MICROSCOPY SYSTEM	BRUCE, MICHAEL R.
<u>09583617</u>	Not Issued	121	05/31/2000	Electrical probing of soi circuits	BRUCE, MICHAEL R.
<u>09586505</u>	<u>6549022</u>	150	06/02/2000	APPARATUS AND METHOD FOR ANALYZING FUNCTIONAL FAILURES IN INTEGRATED CIRCUITS	BRUCE, MICHAEL R.
<u>09586518</u>	Not Issued	95	06/02/2000	RESISTIVITY ANALYSIS	BRUCE, MICHAEL R.
<u>09586572</u>	<u>6546513</u>	150	06/02/2000	DATA PROCESSING DEVICE TEST APPARATUS AND METHOD THEREFOR	BRUCE, MICHAEL R.
<u>09613667</u>	<u>6500699</u>	150	07/11/2000	TESTING OF SOI DIE	BRUCE, MICHAEL R.
<u>09654823</u>	<u>6375347</u>	150	09/05/2000	METHOD FOR LASER SCANNING FLIP-CHIP INTEGRATED CIRCUITS	BRUCE, MICHAEL R.
<u>09750454</u>	Not Issued	168	12/28/2000	Nanomachining method for integrated circuits	BRUCE, MICHAEL R.
<u>09750644</u>	Not Issued	160	12/28/2000	Nanomachining of integrated circuits	BRUCE, MICHAEL R.
<u>09750650</u>	Not Issued	168	12/28/2000	Optical analysis of integrated circuits	BRUCE, MICHAEL R.
<u>09750651</u>	Not Issued	168	12/28/2000	Circuit access and analysis for a SOI flip-chip die	BRUCE, MICHAEL R.
<u>09751097</u>	Not Issued	161	12/28/2000	SOI die analysis of circuitry logic states via coupling through the insulator	BRUCE, MICHAEL R.
<u>09755005</u>	<u>6403388</u>	150	01/05/2001	NANOMACHINING METHOD FOR INTEGRATED CIRCUITS	BRUCE, MICHAEL R.
<u>09755008</u>	Not Issued	121	01/05/2001	Optical analysis of integrated circuits	BRUCE, MICHAEL R.
<u>09755011</u>	<u>6472760</u>	150	01/05/2001	NANOMACHINING OF INTEGRATED CIRCUITS	BRUCE, MICHAEL R.
<u>09755012</u>	<u>6621281</u>	150	01/05/2001	SOI DIE ANALYSIS OF CIRCUITRY LOGIC STATES VIA COUPLING THROUGH THE INSULATOR	BRUCE, MICHAEL R.
<u>09755013</u>	<u>6448095</u>	150	01/05/2001	CIRCUIT ACCESS AND ANALYSIS FOR A SOI FLIP-CHIP DIE	BRUCE, MICHAEL R.
<u>09766472</u>	Not Issued	163	01/19/2001	Semiconductor die analysis using above band-gap energy	BRUCE, MICHAEL R.

09833247	Not Issued	71	04/11/2001	Three-dimensional tomography	BRUCE, MICHAEL R.
09833250	6566888	150	04/11/2001	REPAIR OF RESISTIVE ELECTRICAL CONNECTIONS IN AN INTEGRATED CIRCUIT	BRUCE, MICHAEL R.
09864656	6448096	150	05/23/2001	ATOMIC FORCE MICROSCOPY AND SIGNAL ACQUISITION VIA BURIED INSULATOR	BRUCE, MICHAEL R.
09864665	6621288	150	05/23/2001	TIMING MARGIN ALTERATION VIA THE INSULATOR OF A SOI DIE	BRUCE, MICHAEL R.

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Sample Die. for FA. Baseline. Goal. 30%. 4 5 %. No. Yes. No. Yes. 80-95%. 90-99%. Days.

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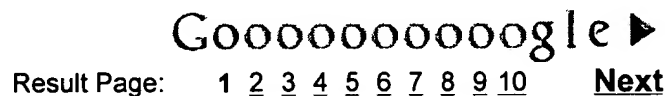
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Figure 9(b) shows the **SEM** image of the **defect**. ... **FIB** may be used to expose otherwise hidden **circuit** components for contact or contactless probing or may ...
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